

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination LAM ET AL.	
		Examiner Peter Y. Choi	Art Unit 1771	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,875,711	04-2005	Chen et al.	442/72
	B	US-			
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	E	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	EP 1203897 A1	05-2002	European Patent	LAM et al.	
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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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